



B 8FW

843.41106X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: K. ASAYAMA, et al.  
Application No.: 10/051,056  
Filed: January 22, 2002  
For: METHOD FOR MANUFACTURING A SEMICONDUCTOR  
DEVICE TO PROVIDE A PLURALITY OF TEST ELEMENT  
GROUPS (TEGs) IN A SCRIBE REGION (As Amended)  
Art Unit: 2829  
Examiner: E. T. Pert  
CONF. No. 1783  
Allowed: September 27, 2004 **Issue Fee Not Yet Paid**

**AMENDMENT PURSUANT TO 37 CFR §1.312**

**MS: ISSUE FEE**  
Commissioner For Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

October 15, 2004

Sir:

Please amend the above-identified application as listed below and as set forth  
on the following pages:

**Amendments to the Specification; and**

**Remarks are included following the amendments.**